

Substitute for form 1449A/PTO & 1449B/PTO		Complete if Known	
SECOND INFORMATION DISCLOSURE STATEMENT BY APPLICANT <small>(use as many sheets as necessary)</small>		Application Number	10/699,879
		Filing Date	November 4, 2003
		First Named Inventor	Sang-min Yoon et al.
		Examiner Name	Unassigned
		Attorney Docket Number	033808-007
Sheet 01 of 1			

U.S. PATENT DOCUMENTS				
Examiner Initials	Document Number	Kind Code (if known)	Name of Patentee or Applicant of Cited Document	Issue/Publication Date (MM-DD-YYYY)

FOREIGN PATENT DOCUMENTS						
Examiner Initials	Document Number	Kind Code (if known)	Country	Date of Publication (MM-DD-YYYY)	Translation	
					Yes	No

NON-PATENT LITERATURE DOCUMENTS	
Examiner Initials	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.
DR	European Search Report dated February 26, 2004 for corresponding application EP 03 25 6953
	TAE-KYUNKIM ET AL., "Component-Based LDA Face Descriptor for Image Retrieval", Proceedings of the 13 th British Machine Vision Conference, 2002, pgs. 507-516, Vol. 2, Cardiff University, England
	DAVID J. OZIEM, "Face Recognition Techniques and the Implications of Facial Transformations", Bachelor Dissertation, Computer Science Department, 2002, pgs. 17-34, University of Bristol, England
	G.A. MOTA ET AL., "Face Detector Combining Eigenfaces, Neural Network and Bootstrap", Proc. Brazilian Symposium on neural Networks, 2000, page 290, Left-hand column, Paragraph 5,
	HYUN-CHUL KIM ET AL., "Face Recognition Using the Mixture-of-Eigenfaces Method", Pattern Recognition Letters, 2002, pgs. 1549-1588, Elsevier Science B.V.
✓	ALEX M. MARTINEZ ET AL., "PCA Versus LDA", IEEE Transactions on Pattern Analysis and Machine Intelligence, 2001, pgs. 228-233, Vol. 23, No. 2, IEEE Inc., New York, USA

Examiner Signature	<i>[Signature]</i>	Date Considered	2/12/07
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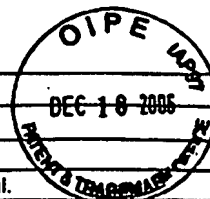
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with M.P.E.P. § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.
VA 137231.1

THIRD INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(use as many sheets as necessary)

Sheet 1 of 1

Application Number	10/699,879
Filing Date	November 4, 2003
First Named Inventor	Sang-min Yoon et al.
Examiner Name	Unassigned
Attorney Docket No.	1033808-000007



U.S. PATENT DOCUMENTS

Examiner Initials	Document Number	Kind Code (if known)	Name of Patentee or Applicant of Cited Document	Issue/Publication Date (MM-DD-YYYY)

FOREIGN PATENT DOCUMENTS

Examiner Initials	Document Number	Kind Code (if known)	Country	Date of Publication (MM-DD-YYYY)	STATUS						
					Translation	Partial Translation	Eng. Lang. Summary	Official Action	IPER	Abstract	Cited in Spec
DR	2001-169272	A	JP	06-22-2001				X		X	
	08-083341	A	JP	03-26-1996				X		X	
	2001-092963	A	JP	04-06-2001				X		X	

NON-PATENT LITERATURE DOCUMENTS

Examiner Initials	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.
DR	Official Action issued by the Japanese Patent Office in corresponding JP Application No. 2003-374316, September 27, 2006, JAPAN
DR	Yingjie WANG et al., "Facial feature detection and face recognition from 2D and 3D images", Pattern Recognition Letters (an official publication of the International Association for Pattern Recognition), August 2002, pp. 1191-1202, Volume 23, Number 10, Elsevier B.V., North-Holland

Examiner Signature	Date Considered	2/17/07
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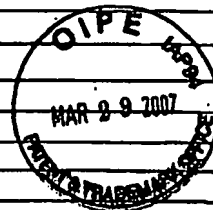
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FOURTH
INFORMATION DISCLOSURE
STATEMENT BY APPLICANT

(use as many sheets as necessary)

Sheet 1 of 1

Application Number	10/699,879
Filing Date	November 4, 2003
First Named Inventor	Sang-min Yoon et al.
Examiner Name	DENNIS ROSARIO
Attorney Docket No.	1033808-000007

**U.S. PATENT DOCUMENTS**

Examiner Initials	Document Number	Kind Code (if known)	Name of Patentee or Applicant of Cited Document	Issue/Publication Date (MM-DD-YYYY)

FOREIGN PATENT DOCUMENTS

Examiner Initials	Document Number	Kind Code (if known)	Country	Date of Publication (MM-DD-YYYY)	STATUS						
					Translation	Partial Translation	Eng. Lang. Summary	Search Report	IPER	Abstract	Cited in Spec

NON-PATENT LITERATURE DOCUMENTS

Examiner Initials	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.
DR	Summons to attend oral proceedings pursuant to Rule 71(1) EPC and attached Communication, issued by the European Patent Office on January 3, 2007 in corresponding European Patent Application No. 03256953.5, EPO, Munich, DE
↓	MÜLLER, KLAUS-ROBERT, et al., "An Introduction to Kernel-Based Learning Algorithms", IEEE Transactions on Neural Networks, March 2001, Vol. 12, No. 2, IEEE, USA

Examiner Signature

Date Considered

5/17/07

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